

ABSTRACT

Provided is a conductive film coated substrate, including a conductive film formed thereon. In a relationship between a bearing area (%) and a bearing depth (nm) that are obtained by measuring, with an atomic force microscope, a region of $1\text{ }\mu\text{m} \times 1\text{ }\mu\text{m}$ of a surface of the conductive film, the surface of the conductive film satisfies a relationship that $(BA_{70}-BA_{30})/(BD_{70}-BD_{30})$ is 15 or more and 260 or less (%/nm), and a maximum height (R_{max}) is 1.3 nm or more and 15 nm or less.